# **Protected Power MOSFET**

2.6 A, 52 V, N–Channel, Logic Level, Clamped MOSFET w/ ESD Protection

#### Features

- Diode Clamp Between Gate and Source
- ESD Protection Human Body Model 5000 V
- Active Over-Voltage Gate to Drain Clamp
- Scalable to Lower or Higher R<sub>DS(on)</sub>
- Internal Series Gate Resistance
- These are Pb–Free Devices

#### Benefits

- High Energy Capability for Inductive Loads
- Low Switching Noise Generation

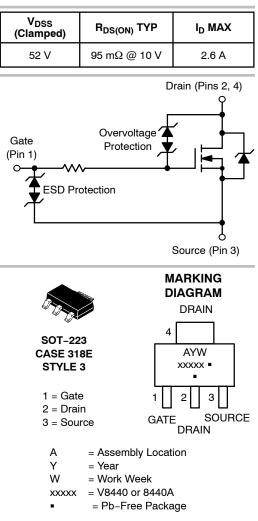
#### Applications

- Automotive and Industrial Markets: Solenoid Drivers, Lamp Drivers, Small Motor Drivers
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable



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(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 8 of this data sheet.

# **MAXIMUM RATINGS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-to-Source Voltage Internally Clamped	V <sub>DSS</sub>	52–59	V
Gate-to-Source Voltage - Continuous	V <sub>GS</sub>	±15	V
Drain Current – Continuous @ T <sub>A</sub> = 25°C – Single Pulse (t <sub>p</sub> = 10 $\mu s$ ) (Note 1	, I <sub>D</sub>	2.6 10	A
Total Power Dissipation @ $T_A = 25^{\circ}C$ (Note 1)	PD	1.69	W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C
Single Pulse Drain–to–Source Avalanche Energy (V_DD = 50 V, I_D(pk) = 1.17 A, V_GS = 10 V, L = 160 mH, R_G = 25 $\Omega$ )	E <sub>AS</sub>	110	mJ
Load Dump Voltage (V_{GS} = 0 and 10 V, R_I = 2.0 $\Omega,~R_L$ = 9.0 $\Omega,~td$ = 400 ms)	V <sub>LD</sub>	60	V
Thermal Resistance, Junction-to-Ambient (Note 1 Junction-to-Ambient (Note 2		74 169	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 10 Seconds	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.
1. When surface mounted to a FR4 board using 1" pad size, (Cu area 1.127 in<sup>2</sup>).
2. When surface mounted to a FR4 board using minimum recommended pad size, (Cu area 0.412 in<sup>2</sup>).

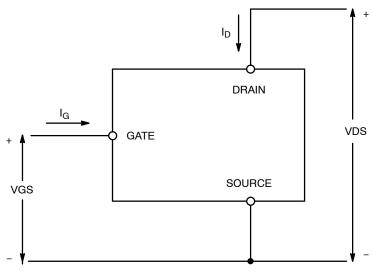


Figure 1. Voltage and Current Convention

#### MOSFET ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Charac	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS				•		
Drain-to-Source Breakdown Voltage (Note 3) ( $V_{GS} = 0 V$ , $I_D = 1.0 mA$ , $T_J = 25^{\circ}C$ ) ( $V_{GS} = 0 V$ , $I_D = 1.0 mA$ , $T_J = -40^{\circ}C$ to 125°C) (Note 4) Temperature Coefficient (Negative)		V <sub>(BR)DSS</sub>	52 50.8	55 54 –9.3	59 59.5	V V mV/°C
Zero Gate Voltage Drain Current ( $V_{DS}$ = 40 V, $V_{GS}$ = 0 V) ( $V_{DS}$ = 40 V, $V_{GS}$ = 0 V, $T_{J}$ = 125°C)	I <sub>DSS</sub>			10 25	μΑ	
$\begin{array}{l} Gate-Body \ Leakage \ Current \\ (V_{GS}=\pm 8 \ V, \ V_{DS}=0 \ V) \\ (V_{GS}=\pm 14 \ V, \ V_{DS}=0 \ V) \end{array}$	I <sub>GSS</sub>		±35	±10	μΑ	
ON CHARACTERISTICS (Note 3)						
Gate Threshold Voltage (Note 3) $(V_{DS} = V_{GS}, I_D = 100 \ \mu A)$ Threshold Temperature Coefficient (Negative)		V <sub>GS(th)</sub>	1.1	1.5 -4.1	1.9	V mV/°C
Static Drain-to-Source On-Resistance (Note 3) ( $V_{GS} = 3.5 \text{ V}, I_D = 0.6 \text{ A}$ ) ( $V_{GS} = 4.0 \text{ V}, I_D = 1.5 \text{ A}$ ) ( $V_{GS} = 10 \text{ V}, I_D = 2.6 \text{ A}$ )		R <sub>DS(on)</sub>		150 135 95	180 160 110	mΩ
Forward Transconductance (Note 3) (V	<sub>oS</sub> = 15 V, I <sub>D</sub> = 2.6 A)	<b>9</b> FS		3.8		Mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance		C <sub>iss</sub>		155		pF
Output Capacitance	V <sub>DS</sub> = 35 V, V <sub>GS</sub> = 0 V, f = 10 kHz	C <sub>oss</sub>		60		
Transfer Capacitance		C <sub>rss</sub>		25		
Input Capacitance		C <sub>iss</sub>		170		pF
Output Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 10 kHz	C <sub>oss</sub>		70		
Transfer Capacitance		C <sub>rss</sub>		30		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2%.

4. Not subject to production testing.
 5. Switching characteristics are independent of operating junction temperatures.

### **MOSFET ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit		
SWITCHING CHARACTERISTICS (Note 5)								
Turn-On Delay Time		t <sub>d(on)</sub>		375		ns		
Rise Time	V <sub>GS</sub> = 4.5 V, V <sub>DD</sub> = 40 V,	t <sub>r</sub>		1525				
Turn-Off Delay Time	$I_{\rm D} = 2.6 \text{ A}, \text{ R}_{\rm D} = 15.4 \Omega$	t <sub>d(off)</sub>		1530				
Fall Time		t <sub>f</sub>		1160				
Turn-On Delay Time		t <sub>d(on)</sub>		325		ns		
Rise Time	V <sub>GS</sub> = 4.5 V, V <sub>DD</sub> = 40 V,	t <sub>r</sub>		1275				
Turn-Off Delay Time	$V_{GS} = 4.5 \text{ V}, V_{DD} = 40 \text{ V}, \\ I_D = 1.0 \text{ A}, \text{ R}_D = 40 \Omega$	t <sub>d(off)</sub>		1860				
Fall Time		t <sub>f</sub>		1150				
Turn-On Delay Time		t <sub>d(on)</sub>		190		ns		
Rise Time	V <sub>GS</sub> = 10 V, V <sub>DD</sub> = 15 V,	t <sub>r</sub>		710				
Turn-Off Delay Time	$I_{\rm D}$ = 2.6 A, $R_{\rm D}$ = 5.8 $\Omega$	t <sub>d(off)</sub>		2220				
Fall Time		t <sub>f</sub>		1180				
Gate Charge		Q <sub>T</sub>		4.5		nC		
	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 40 V, I <sub>D</sub> = 2.6 A (Note 3)	Q <sub>1</sub>		0.9				
		Q <sub>2</sub>		2.6				
Gate Charge		Q <sub>T</sub>		3.9		nC		
	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 15 V, I <sub>D</sub> = 1.5 A (Note 3)	Q <sub>1</sub>		1.0		1		
		Q <sub>2</sub>		1.7		1		
SOURCE-DRAIN DIODE CHARA	ACTERISTICS							
Forward On-Voltage	$l_{0} = 2.6 \text{ A} / V_{00} = 0.1/ (Note 3)$	Ver		0.81	15	V		

Forward On-Voltage	$I_{S}$ = 2.6 A, $V_{GS}$ = 0 V (Note 3) $I_{S}$ = 2.6 A, $V_{GS}$ = 0 V, $T_{J}$ = 125°C	V <sub>SD</sub>	0.81 0.66	1.5	V
Reverse Recovery Time		t <sub>rr</sub>	730		ns
	I <sub>S</sub> = 1.5 A, V <sub>GS</sub> = 0 V, dI <sub>s</sub> /dt = 100 A/μs (Note 3)	t <sub>a</sub>	200		
		t <sub>b</sub>	530		
Reverse Recovery Stored Charge		Q <sub>RR</sub>	6.3		μC

#### ESD CHARACTERISTICS (Note 4)

Electro-Static Discharge Capability	Human Body Model (HBM)	ESD	5000		V
	Machine Model (MM)		500		

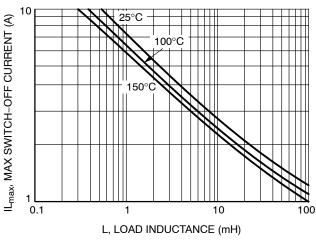
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Pulse Test: Pulse Width  $\leq$  300  $\mu s,$  Duty Cycle  $\leq$  2%.

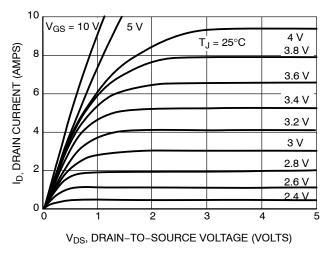
4. Not subject to production testing.

5. Switching characteristics are independent of operating junction temperatures.

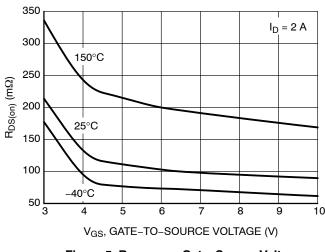
#### **TYPICAL PERFORMANCE CURVES**













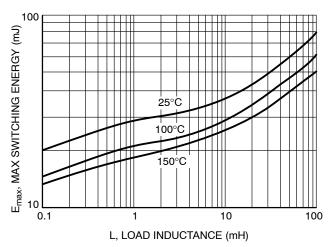


Figure 2. Single Pulse Maximum Switching Energy vs. Load Inductance

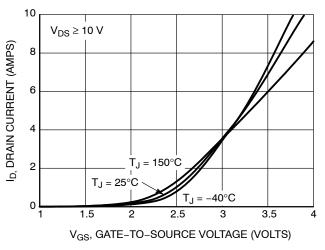


Figure 4. Transfer Characteristics

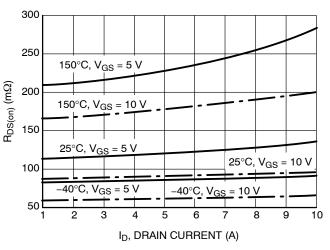
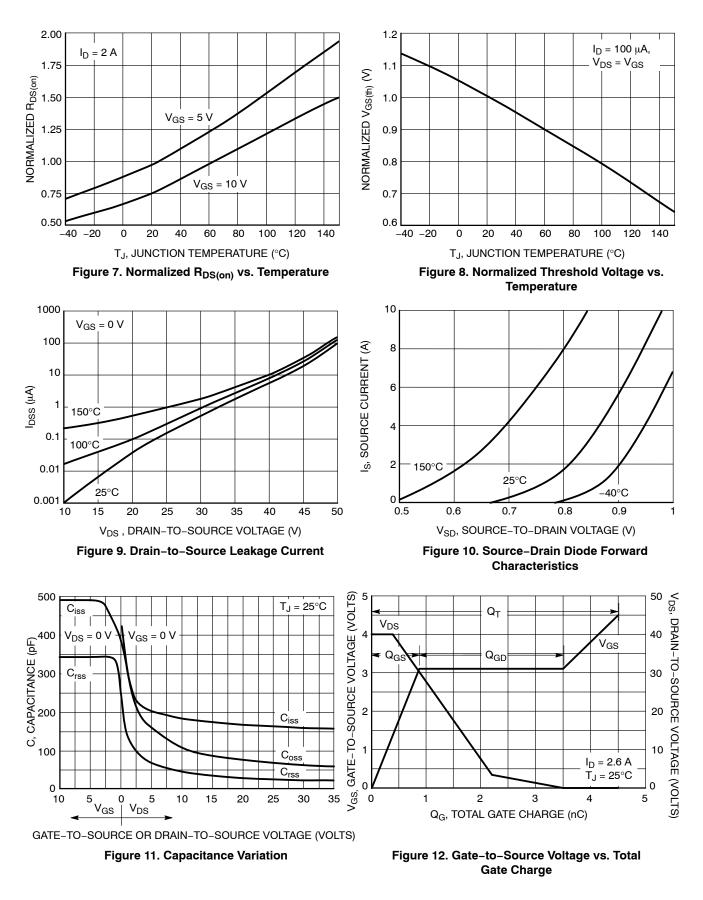
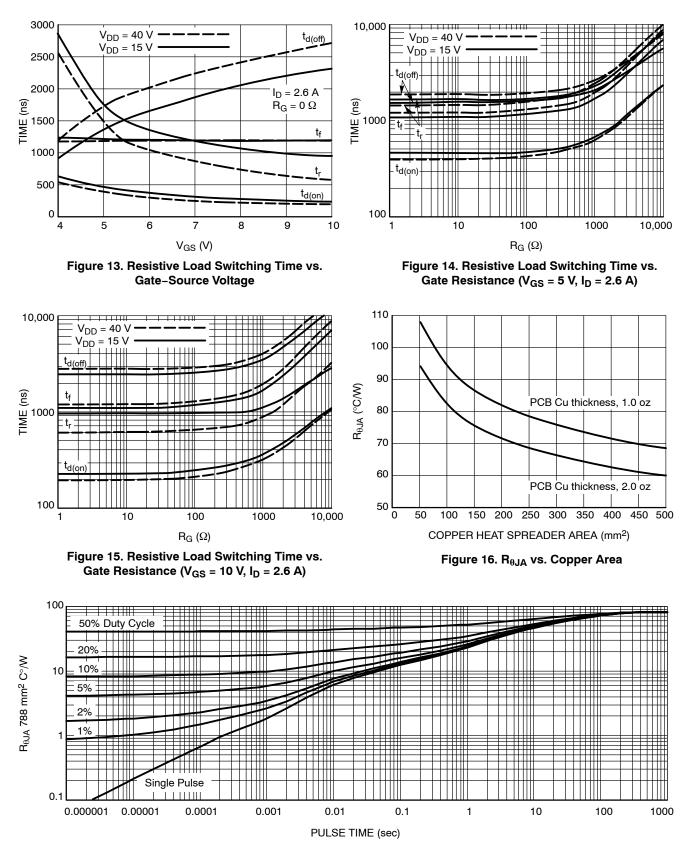


Figure 6. R<sub>DS(on)</sub> vs. Drain Current

#### **TYPICAL PERFORMANCE CURVES**



#### **TYPICAL PERFORMANCE CURVES**





#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NCV8440STT1G	SOT-223 (Pb-Free)	1000 / Tape & Reel
NCV8440ASTT1G	SOT-223 (Pb-Free)	1000 / Tape & Reel
NCV8440STT3G	SOT-223 (Pb-Free)	4000 / Tape & Reel
NCV8440ASTT3G	SOT-223 (Pb-Free)	4000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

DATE 02 OCT 2018

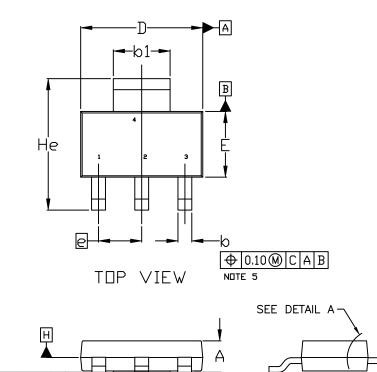




SCALE 1:1

0.10 C

A1



-11

SIDE VIEW

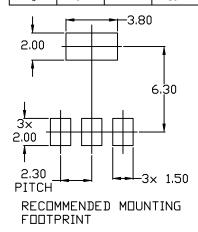
DETAIL A

NDTES:

SOT-223 (TO-261) CASE 318E-04 ISSUE R

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. DIMENSIONS D & E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.200MM PER SIDE.
- 4. DATUMS A AND B ARE DETERMINED AT DATUM H.
- 5. ALLS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST PDINT OF THE PACKAGE BODY.
- 6. POSITIONAL TOLERANCE APPLIES TO DIMENSIONS 6 AND 61.

	MILLIMETERS				
DIM	MIN.	NDM.	MAX.		
A	1.50	1.63	1.75		
A1	0.02	0.06	0.10		
b	0.60	0.75	0.89		
b1	2.90	3.06	3.20		
с	0.24	0.29	0.35		
D	6.30	6.50	6.70		
E	3.30	3.50	3.70		
e		2.30 BSC			
L	0.20				
L1	1.50	1.75	2.00		
He	6.70	7.00	7.30		
θ	0*		10*		



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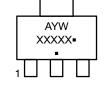
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#### SOT-223 (TO-261) CASE 318E-04 ISSUE R

#### DATE 02 OCT 2018

STYLE 1: PIN 1. BASE 2. COLLECTOR 3. EMITTER 4. COLLECTOR	STYLE 2: PIN 1. ANODE 2. CATHODE 3. NC 4. CATHODE	STYLE 3: PIN 1. GATE 2. DRAIN 3. SOURCE 4. DRAIN	STYLE 4: PIN 1. SOURCE 2. DRAIN 3. GATE 4. DRAIN	STYLE 5: PIN 1. DRAIN 2. GATE 3. SOURCE 4. GATE
STYLE 6: PIN 1. RETURN 2. INPUT 3. OUTPUT 4. INPUT	STYLE 7: PIN 1. ANODE 1 2. CATHODE 3. ANODE 2 4. CATHODE	STYLE 8: CANCELLED	Style 9: Pin 1. Input 2. Ground 3. Logic 4. Ground	STYLE 10: PIN 1. CATHODE 2. ANODE 3. GATE 4. ANODE
STYLE 11: PIN 1. MT 1 2. MT 2 3. GATE 4. MT 2	Style 12: Pin 1. Input 2. Output 3. NC 4. Output	STYLE 13: PIN 1. GATE 2. COLLECTOR 3. EMITTER 4. COLLECTOR		

# GENERIC MARKING DIAGRAM\*



- A = Assembly Location
- Y = Year
- W = Work Week
- XXXXX = Specific Device Code
- = Pb-Free Package
- (Note: Microdot may be in either location) \*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

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